## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Smith, et al. Attorney Docket No.: KLA1P095/P1072

Application No.: NEW Examiner: UNASSIGNED

Filed: HEREWITH Group: UNASSIGNED

Title: DEFECT DETECTION USING MULTIPLE SENSORS AND PARALLEL PROCESSING

## INFORMATION DISCLOSURE STATEMENT 37 CFR §§1.56 AND 1.97(b)

Mail Stop Patent Application Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

The references listed in the attached PTO Form 1449, copies of which are attached, may be material to examination of the above-identified patent application. Applicants submit these references in compliance with their duty of disclosure pursuant to 37 CFR §§1.56 and 1.97. The Examiner is requested to make these references of official record in this application.

This Information Disclosure Statement is not to be construed as a representation that a search has been made, that additional information material to the examination of this application does not exist, or that these references indeed constitute prior art.

This Information Disclosure Statement is: (i) filed within three (3) months of the filing date of the above-referenced application, (ii) believed to be filed before the mailing date of a first Office Action on the merits, or (iii) believed to be filed before the mailing of a first Office Action after the filing of a Request for Continued Examination under §1.114. Accordingly, it is believed that no fees are due in connection with the filing of this Information Disclosure Statement. However, if it is determined that any fees are due, the Commissioner is hereby authorized to charge such fees to Deposit Account 500388 (Order No. KLA1P095).

Respectfully submitted,

BEYER WEAVER & THOMAS, LLP

Phillip P. Lee

Registration No. 46,866

Form 1449 (Modified)	Atty Docket No. KLA1P095/P1072	Application No.: UNASSIGNED
Information Disclosure	Applicant:	UNASSIGNED
Statement By Applicant	Smith et al.	
	Filing Date	Group
(Use Several Sheets if Necessary)	HEREWITH	UNASSIGNED

## **U.S. Patent Documents**

Examiner						Sub-	Filing
Initial	No.	Patent No.	Date	Patentee	Class	class	Date
	Α						
	В						
	С						
	D						
	E						
	F						
	G						
	Н						
	I						

Foreign Patent or Published Foreign Patent Application

Examiner	Document		Publication	Country or		Sub-	Translation	
Initial	No.	No.	Date .	Patent Office	Class	class	Yes	No
	J	WO00/68673	11/16/00	WIPO			X	
	K							
	L	,			1		1	
	M		_					
	N				Ì			

## **Other Documents**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication	
	0		
	P		
	Q		
Examiner		Date Considered	

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.